

From Dean's Desk:

To meet the challenge of ensuring excellence in engineering education, the issue of quality needs to be addressed, debated and taken forward in a systematic manner. Accreditation is the principal means of quality assurance in higher education. The major emphasis of accreditation process is to measure the outcomes of the program that is being accredited. In line with this Faculty of Technology of University of Mumbai has taken a lead in incorporating philosophy of outcome based education in the process of curriculum development.

Faculty of Technology, University of Mumbai, in one of its meeting unanimously resolved that, each Board of Studies shall prepare some Program Educational Objectives (PEO's) and give freedom to affiliated Institutes to add few (PEO's) and course objectives and course outcomes to be clearly defined for each course, so that all faculty members in affiliated institutes understand the depth and approach of course to be taught, which will enhance learner's learning process. It was also resolved that, maximum senior faculty from colleges and experts from industry to be involved while revising the curriculum. I am happy to state that, each Board of studies has adhered to the resolutions passed by Faculty of Technology, and developed curriculum accordingly. In addition to outcome based education, semester based credit and grading system is also introduced to ensure quality of engineering education.

Semester based Credit and Grading system enables a much-required shift in focus from teacher-centric to learnercentric education since the workload estimated is based on the investment of time in learning and not in teaching. It also focuses on continuous evaluation which will enhance the quality of education. University of Mumbai has taken a lead in implementing the system through its affiliated Institutes and Faculty of Technology has devised a transparent credit assignment policy and adopted ten points scale to grade learner's performance. Credit assignment for courses is based on 15 weeks teaching learning process, however content of courses is to be taught in 12-13 weeks and remaining 3-2 weeks to be utilized for revision, guest lectures, coverage of content beyond syllabus etc.

Credit and grading based system was implemented for First Year of Engineering from the academic year 2012-2013. Subsequently this system will be carried forward for Second Year Engineering in the academic year 2013-2014, for Third Year and Final Year Engineering in the academic years 2014-2015 and 2015-2016 respectively.

Dr. S. K. Ukarande Dean, Faculty of Technology, Member - Management Council, Senate, Academic Council University of Mumbai, Mumbai

Preamble:

The engineering education in India in general is expanding in manifolds. Now, the challenge is to ensure its quality to the stakeholders along with the expansion. To meet this challenge, the issue of quality needs to be addressed, debated and taken forward in a systematic manner. Accreditation is the principal means of quality assurance in higher education and reflects the fact that in achieving recognition, the institution or program of study is committed and open to external review to meet certain minimum specified standards. The major emphasis of this accreditation process is to measure the outcomes of the program that is being accredited. Program outcomes are essentially a range of skills and knowledge that a student will have at the time of graduation from the program. An engineering program must ensure that its graduates understand the basic concepts of science and mathematics, have gone through one engineering field in dept of appreciate and use its methodologies of analyses and design, and have acquired skills for lifelong learning.

An engineering program must therefore have a mission statement which is in conformity with program objectives and program outcomes that are expected of the educational process. The outcomes of a program must be measureable and must be assessed regularly through proper feedback for improvement of the programme. There must be a quality assurance process in place within the Institute to make use of the feedback for improvement of the programme. The curriculum must be constantly refined and updated to ensure that the defined objectives and outcomes are achieved. Students must be encouraged to comment on the objectives and outcomes and the role played by the individual courses in achieving them. In line with this Faculty of Technology of University of Mumbai has taken a lead in incorporating philosophy of outcome based education in the process of curriculum development.

I, as Chairman, Board of Studies in Electronics Engineering University of Mumbai, is happy to state here that, Program Educational Objectives were finalized in a meeting where more than 20 members from different Institutes have attended, who were either Heads or their representatives of Electronics Engineering Department. The Program Educational Objectives finalized for undergraduate program in Electronics Engineering are listed below;

- To provide students with a strong foundation in the mathematical, scientific and engineering fundamentals necessary to formulate, solve and analyze engineering problems at hand and to prepare them for graduate studies.
- To prepare students to demonstrate an ability to identify, formulate and solve electronics engineering problems.
- To prepare students to demonstrate ability to design electrical and electronics systems and conduct experiments, analyze and interpret data.
- To prepare students to demonstrate for successful career in industry to meet needs of Indian and multi-national companies.
- To develop the ability among students to synthesize data and technical concepts from applications to product design.
- To provide opportunity to students to work as part of teams on multidisciplinary projects.
- To promote awareness among students for the life-long learning and to introduce them to professional ethics and codes of professional practice.

In addition to above more program educational objectives of their own may be added by affiliated Institutes and Heads of Departments.

In addition to Program Educational Objectives, for each course of undergraduate program, objectives and expected outcomes from learner's point of view are also included in the curriculum to support the philosophy of outcome based education. I believe strongly that small step taken in right direction will definitely help in providing quality education to the stake holders.

Dr. Dileep G. Borse

M. Tech. Ph. D. (E E with Specialization in Microelectronics) I I T Bombay Chairman, Board of Studies in Electronics Engineering University of Mumbai

		Credit	and Evaluation	ation Schei	me			
			<u>Semester</u>	r III				
Sub	Subject Name	Teachiı	ng Scheme	(Hrs.)		Credits Assi	gned	
Code		Theory	Practical	Tutorial	Theory	Practical/TW	Tutorial	Total
EXS301	*Applied Mathematics	04		01	04		01	05
	III							
EXC302	Electronic Devices	04			04			04
EXC303	Digital Circuits and	04			04			04
	Design							
EXC304	Circuit Theory	04			04			04
EXC305	Electronic Instruments	04			04			04
	and Measurements							
EXL301	Electronic Devices		02			01		01
	Laboratory							
EXL302	Digital Circuits and		02			01		01
	Design							
	Laboratory							
EXL303	Circuit Theory and		02			01		01
	Measurements							
	Laboratory							
EXL304	*Object Oriented		02+02**			02		02
	Programming							
	Methodology							
	Laboratory							
Total		20	10	01	20	04	01	26

SE Electronics Engineering Semester III Credit and Evaluation Scheme Semester III

*Common subject with EXTC, Electrical Engg. Instrumentation Engg, Biomedical Engg.

** 2 Hours be converted to theory for entire class and 2 hour for hands on practice.

Subject	Subject Name			Exa	minatior	Scheme	9		
Code	_		The	ory Marks		Term	Practical	Oral	Total
		Inte	rnal As	ssessment	End	Work	and		
		Test 1	Test	Ave. of	Sem.		Oral		
			2	Test 1 and	Exam				
				Test 2					
EXS301	*Applied Mathematics III	20	20	20	80	***25			125
EXC302	Electronic Devices	20	20	20	80				100
EXC303	Digital Circuits and	20	20	20	80				100
	Design								
EXC304	Circuit Theory	20	20	20	80				100
EXC305	Electronic Instruments and	20	20	20	80				100
	Measurements								
EXL301	Electronic Devices					25	50		75
	Laboratory								
EXL302	Digital Circuits and					25	50		75
	Design Laboratory								
EXL303	Circuit Theory and					25			25
	Measurements Laboratory								
EXL304	*Object Oriented					25	50		75
	Programming Laboratory								
				100	400	125	150		775

*Common subject with EXTC, Electrical Engg, Instrumentation Engg., Biomedical Engg.

*** Tutorial work will be assessed as term work

SE Electronics Engineering Semester III Syllabus of Theory Subjects

Subject Code	Subject Name	Т	eaching Sche	eme	Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial- work	Total
EXS	Applied	04		01	04	-	01	05
301	Mathematics III							

Subject	Subject Name				Examinatio	on Scheme			
Code			Т	heory Marks		Tutorial	Practical	Oral	Total
		In	Internal assessment End			as Term			
		Test	Test	Ave. Of	Sem.	Work			
		1	2	Test 1 and	Exam				
				Test 2					
EXS	Applied	20	20	20	80	25			125
301	Mathematics III								

Course Prerequisite:

FE C 101: Applied Mathematics I FE C 201: Applied Mathematics II

Course Objective:

- To provide students with a sound foundation in Mathematics and prepare them for graduate studies in Electronics Engineering
- To make students to understand mathematics' fundamentals necessary to formulate, solve and analyze engineering problems.

Expected Outcome:

- Students will demonstrate basic knowledge of Laplace Transform. Fourier Series, Bessel Functions, Vector Algebra and Complex Variable.
- Students will demonstrate an ability to identify formulate and solve electronics Engineering problems using Applied Mathematics.
- Students will show the understanding of impact of engineering mathematics in the engineering
- Students will become capable and eligible to participate and succeed in competitive exams like GATE, GRE.

Module No.	Unit No.	Topics	Hrs.
1.0	110.	Laplace Transform	12
	1.1	Laplace transform (LT) of standard functions: Definition. Unilateral and bilateral Laplace transform, LT of $sin(at)$, $cos(at)$, e^{at} , t^{n} , $sinh(at)$, $cosh(at)$, $erf(t)$, Heavi-side unit step, direct- delta function, LT of periodic function	
	1.2	Properties of Laplace transform: linearity, first shifting theorem, second shifting theorem, multiplication by t^n , division by t , Laplace transform derivatives and integrals, change of scale, convolution theorem, initial and final value theorem, Parsevel's identity	
	1.3	Inverse Laplace Transform: Partial fraction method, long division method, residue method, theorem of LT to find inverse	
	1.4	Applications of Laplace transform : Solution of ordinary differential equations	
2.0		Fourier Series	10
	2.1	Introduction: Definition, Dirichlet's conditions, Euler's formulae	
	2.2	Fourier series of functions: exponential, trigonometric functions, even and odd functions, half range sine and cosine series	
	2.3	Complex form of Fourier series, Fourier integral representation	
3.0		Bessel functions	08
	3.1	Solution of Bessel differential equation: series method, recurrence relation, properties of Bessel Function of order $+1/2$ and $-1/2$	
	3.2	Generating function, orthogonality property	
	3.3	Bessel Fourier series of a functions	
4.0		Vector Algebra	12
	4.1	Scalar and vector product : Scalar and vector product of three and four vectors and their properties	
	4.2	Vector differentiation : Gradient of scalar point function, divergence and curl of vector pint function	
	4.3	Properties: Solenoidal and Irrotational vector fields, conservative vector field	
	4.4	Vector integral: Line integral, Green's theorem in a plane, Gauss Divergence theorem, Stokes' theorem	
5.0		Complex Variable	10
	5.1	Analytic function: Necessary and sufficient conditions, Cauchy	
		Reiman. equations in polar form	1
	5.2	Harmonic function, orthogonal trajectories	
	5.2 5.3		

Recommended Books

- 1. P. N. Wartikar and J. N. Wartikar, "*A Text Book of Applied Mathematic*", Vol. I & II, Vidyarthi Griha Prakashan, Pune
- 2. A Datta, "Mathematical Methods in Science and Engineerin", 2012
- 3. Dr. B.S. Grewal, "Higher Engineering Mathematics", Khanna Publication
- 4. B. S. Tyagi, "Functions of a Complex Variable," Kedarnath Ram Nath Publication
- 5. B V Ramana, "Higher Engineering Mathematics", Tata McGraw-Hill Publication
- 6. Wylie and Barret, "Advanced Engineering Mathematics", McGraw-Hill 6th Edition
- 7. Erwin Kreysizg, "Advanced Engineering Mathematics", John Wiley & Sons, Inc
- 8. Murry R. Spieget, "Vector Analysis", Schaun's Out Line Series, McGraw Hill Publication

Internal Assessment (IA):

Two tests must be conducted which should cover 80% of syllabus. The average marks of two tests will be considered as final IA marks

End Semester Examination:

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining questions (Q.2 to Q.6) will be set on all the modules.
- 5: Weight age of marks will be as per Blueprint.

Term Work:

At least **08** assignments covering entire syllabus must be given during the **Class Wise Tutorial.** The assignments should be students' centric and an attempt should be made to make assignments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every assignment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

Subject Code	Subject Name	Teach	ning Scheme	Credits Assigned				
		Theory	Practical	Tut.	Theory	TW/Pract.	Tut.	Total
EXC302	Electronic Devices	04		-	04		-	04

	Subject Name	Examination Scheme							
Sub.		Theory	Theory Marks				Pract and	Oral	Total
Code		Internal Assessment End					Oral.		
EXC302	Electronic Devices	Test 1	Test 2	Average of Test1 & Test2	Semester Exam				
		20	20	20	80				100

Prerequisite: FEC105 Basic Electrical & Electronics Engineering Course Objectives:

- 1. To deliver the knowledge about physics of basic semiconductor devices
- 2. To enhance comprehension capabilities of students through understanding of electronic devices
- 3. To introduce and motivate students to the use of advanced microelectronic devices
- 4. To create foundation for forthcoming circuit design courses

- 1. Ability to understand semiconductor devices through energy band diagrams
- 2. Ability to analyze characteristics of semiconductor junctions
- 3. Ability to differentiate between bipolar and unipolar conduction
- 4. Ability to understand physics of optical devices
- 5. Ability to understand working principle of power devices
- 6. Knowledge about advanced semiconductor devices used in research
- 7. Ability to appreciate the role of semiconductor devices in various applications

Module No.	Topics	Hrs.
1.0	Junction Analysis	14
1.1	PN junction Diode: Basic Structure, Energy Band Diagrams, Zero Applied Bias, Forward	
	Applied Bias, Reverse Applied Bias, PN Junction current, Small signal model of PN	
	junction, Generation and recombination of currents, junction breakdown.	
	Zener Diode: Breakdown mechanisms, Characteristics, Effect of Temperature,	
	Application as voltage regulator and backward diode	
	Varactor diode: Working and characteristics	
	Tunnel diode: V-I Characteristics and working	
	TED (Transferred Electron Device): Basic concept, Negative differential resistance, V-I	
	Characteristics and working of Gunn Diode	
	IMPATT: Static and Dynamic Characteristics	

1.2	Metal semiconductor and semiconductor Heterojunctions:	
	Schottkey barrier diode: Qualitative characteristics, Ideal junction properties, Nonideal	
	effects on barrier height and V-I characteristics	
	Metal-semiconductor ohmic contacts: Ideal Non rectifying barriers, Tunneling Barrier, Specific contact resistance	
	Heterojunctions: Heterojunction materials, Energy Band Diagrams, Two dimensional	
	electron gas.	
2	Bipolar Devices	
2.1	BJT: The bipolar transistor action, minority carrier distribution, low-frequency common-	1
	base current gain, non-ideal effects, Ebers-Moll Model, Gummel-Poon Model, Hybrid-Pi Model, Frequency Limitations	
2.2	HBT (Heterojunction bipolar transistor): Current gain in HBT, Basic n-p-n HBT structure	
	with band diagram	
3.0	Field Effect Devices	
3.1	JFET: Construction, operation and device characteristics. V-I relationship and transconductance. Small signal equivalent model, frequency limitation factors and cutoff frequency	
3.2	MOSFET: Two terminal MOS structure, MOSFET construction, Band diagrams under equilibrium and external bias, Threshold Voltage, V-I and CV characteristics, Channel length modulation, Short Channel effects, MOSFET Model	
3.3	MESFET: Device structure, principle of operation, V-I characteristics, High frequency performanceMODFET (i.e HEMT) : Fundamentals, V-I Characteristics, Cutoff Frequency	-
4.0	Optical Devices	
4.1	Optical absorption: Photon absorption coefficient, EHP generation rate Solar Cells: The pn junction, heterojunction and amorphous silicon solar cells	
4.2	Photodetectors:Photoconductor, photodiode, PIN photodiode, APD (avalanche photodiode), phototransistorOptocouplers:Operation, construction, specifications and applications	
5.0	Power Devices	
	PNPN Diode: Basic structure and characteristics	1
5.1	I THE Prodot Duble Structure and characteristics	
5.1	SCR: Basic structure, characteristics, Two transistor analogy.	
5.1		
5.1 5.2	SCR: Basic structure, characteristics, Two transistor analogy.	
	SCR: Basic structure, characteristics, Two transistor analogy. DIAC and TRIAC: Basic Structure and characteristics GTO: Basic structure and characteristics PUT: Operation and characteristics	
	SCR: Basic structure, characteristics, Two transistor analogy. DIAC and TRIAC: Basic Structure and characteristics GTO: Basic structure and characteristics PUT: Operation and characteristics, parameters and UJT as a relaxation oscillator	_
	SCR: Basic structure, characteristics, Two transistor analogy. DIAC and TRIAC: Basic Structure and characteristics GTO: Basic structure and characteristics PUT: Operation and characteristics	_

Recommended Books:

- 1. Donald A. Neamen, "Semiconductor Physics and Devices" Tata MCGraw Hill, Third Edition
- 2. S. M. Sze, "Semiconductor Devices: Physics and Technology", Wiley, Second Edition
- 3. Sung-Mo Kang, Yusuf Leblebici, "CMOS Digital Integrated Circuits", Tata McGraw Hill, Third Edition
- 4. David Bell, "Electronic Devices and Circuits", Oxford, Fifth Edition.
- 5. S Slivahanan and N. Suresh Kumar, "Electronic Devices and Circuits", McGraw Hill, Third Edition
- 6. Gordon W. Roberts and Adel S. Sedra, "Spice", Oxford, Second Edition

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teach	ning Scheme	Credits Assigned				
		Theory	Pract.	Tut.	Theory	TW/Pract.	Tut.	Total
EXC303	Digital Circuits and Design	04		-	04		-	04

	Subject Name	Examination Scheme							
Carl		Theory Marks				TW	Pract.	Oral	Total
Sub. Code		Internal Assessment			End				
EXC303	Digital Circuits and Design	Test 1	Test 2	Average of Test1 & Test2	Semester Exam				
		20	20	20	80		-		100

Prerequisite: FEC105 Basic Electrical & Electronics Engineering

Course Objectives:

- 1. To deliver the knowledge, motivate and train students in logic design
- 2. To introduce the students to various logic gates, SOP, POS and their minimization techniques.
- 3. To explain and describe various logic families and to provide information on different IC's.
- 4. To teach the working of combinational circuits and their applications.
- 5. To make students aware of characteristics of various types of SSI, LSI and MSI devices and their use in various applications.
- 6. To teach students to analyze, understand and design sequential circuits.
- 7. To describe State Machines and explain their design using state diagrams.
- 8. To explain various types of programmable devices
- 9. To train students in writing program with hardware description languages.
- 10. To prepare students for understanding courses like microprocessors, microcontrollers, VLSI design, embedded systems and digital communications

- 1. Ability to develop a logic and apply it to solve real life problems
- 2. Ability to understand current applications, trends and new directions in logic design
- 3. Ability to reduce SOP and POS equations.
- 4. Ability to understand differences between logic families TTL and CMOS
- 5. Ability to understand various SSI, LSI and MSI devices
- 6. Ability to use SSI, LSI and MSI devices in various applications
- 7. Ability to analyze, design and implement combinational circuits
- 8. Ability to analyze, design and implement sequential circuits
- 9. Ability to solve state machines
- 10. Ability to design state machines using state diagrams, State Reduction techniques and State machine synthesis using transition lists
- 11. Ability to understand the concept of simulation, synthesis and implementation
- 12. Ability to use hardware description languages for logic circuit design.

13. Ability to understand programmable logic devices

14. Ability to program CPLD and FPGA

Module No.	Topics	Hrs.
1.0	Fundamentals of Digital Design	14
1.1	Logic Gates: Review of basic gates, Universal gates, Sum of products and products	
	of sum, minimization with Karnaugh Map (upto four variables) and realization.	
1.2	Logic Families: Types of logic families (TTL and CMOS), characteristic parameters	
	(propagation delays, power dissipation, Noise Margin, Fan-out and Fan-in), transfer	
	characteristics of TTL NAND, Interfacing CMOS to TTL and TTL to CMOS.	
1.3	Combinational Circuits using basic gates as well as MSI devices: Half adder, Full	
	adder, Half Subtractor, Full Subtractor, multiplexer, demultiplexer, decoder,	
	Comparator (Multiplexer and demultiplexer gate level upto 4:1).	
	MSI devices IC7483, IC74151, IC74138, IC7485.	1.0
2.0	Elements of Sequential Logic Design :	10
2.1	Sequential Logic: Latches and Flip-Flops (Conversions, timing considerations and	
	metastability are not expected)	
2.2	Counters: Asynchronous, Synchronous Counters, Up Down Counters, Mod	
• •	Counters, Ring Counters Shift Registers, Universal Shift Register	10
3.0	Sequential Logic Design:	10
3.1	Mealy and Moore Machines, Clocked synchronous state machine analysis, State	
	reduction techniques and state assignment, Clocked synchronous state machine	
	design. (Complex word problems like traffic light controller etc. are not expected)	
3.2	MSI counters (7490, 74163, 74169) and applications, MSI Shift registers (74194) and	
4.0	their applications	07
4.0	Programmable Logic Devices:	07
4.1	Concepts of PAL and PLA. Simple logic implementation using PAL and PLA.	
5.0	Introduction to CPLD and FPGA architectures.	07
5.0	Simulation:	07
5.1	Functional Simulation, Timing simulation, Logic Synthesis, RTL	
5.2	Introduction to VHDL, Framework of VHDL Program.	0.5
6.0	Testability:	06
6.1	Fault Models, Stuck at faults, Bridging faults, Controllability and Observability	
6.2	Path sensitization, ATPG, Design for Testability, Boundary Scan Logic, JTAG and Built in self test.	
		52

Recommended Books

- 1. William I. Fletcher, 'An Engineering Approach to Digital Design', PHI.
- 2. B. Holdsworth and R. C. Woods, 'Digital Logic Design', Newnes, 4th Edition
- 3. Morris Mano, Digital Design, Pearson Education, Asia 2002.
- 4. John F. Wakerley, Digital Design Principles And Practices, third Edition Updated, Pearson Education, Singapore, 2002
- 5. Anil K. Maini, Digital Electronics, Principles, Devices and Applications, Wiley
- 6. Stephen Brown and Zvonko Vranesic, Fundamentals of digital logic design with VHDL, McGraw Hill, 2nd Edition.

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	To	eaching Sche	eme	Credits Assigned					
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total		
EXC304	Circuit Theory	04			04			04		

Subject	Subject		Examination Scheme								
Code	Name		T	heory Marks	5	Term	Practical	Oral	Total		
		Inte	ernal as	sessment	End Sem.	Work					
		Test	Test	Ave. of 2	Exam						
		1	2	Tests							
EXC304	Circuit	20	20	20	80				100		
	Theory										

Course Pre-requisite:

FEC 105: Basic Electrical and Electronics Engineering

Partial fraction expansion, matrices, determinants calculus and differential equations,

Course Objectives:

- 1. To analyze the circuits in time and frequency domain
- 2. To study network functions, inter relationship among various circuit parameters, solve more complex network using these parameters.
- 3. To analyze and synthesize circuits and to become familiar with the propagation of signals/wave through transmission lines.

- 1. Through test and laboratory exercises, students will be able to apply their knowledge in solving complex circuits.
- 2. Students will be able to evaluate the time and frequency response which is useful in understanding behavior of electronic circuits and control system.
- 3. Student will be able to understand how the power or information in terms of electromagnetic energy is transmitted through the transmission lines and importance of impedance matching.

Module No.	Unit No.	Topics	Hrs •
1.0		Analysis of Electrical Circuits	09
	1.1	Analysis of DC circuits: Analysis of circuits with and without controlled sources using generalized loop, node matrix, Superposition, Thevenin, Norton, Millman theorems	
	1.2	Analysis of coupled circuits: Self and mutual inductances, coefficient of coupling, Dot convention, equivalent circuit, solution using loop analysis	
	1.3	Series and parallel resonance circuits: Selectivity, bandwidth, quality factor	
2.0		Time and Frequency Domain Analysis	12
	2.1	Time domain analysis of R-L and R-C circuits: Forced and natural response, time constant, initial and final values Solution using first order equation for standard input signals: Transient and steady state time response, solution using universal formula	
	2.2	Time domain analysis of R-L-C circuits: Forced and natural response, effect of damping Solution using second order equation for standard input signals: Transient and steady state time response	
	2.3	Frequency domain analysis of RLC circuits: S-domain representation, applications of Laplace Transform in solving electrical networks, driving point and transfer function, Poles and Zeros, calculation of residues by analytical and graphical method, frequency response	
3.0		Synthesis of RLC Circuits	06
	3.1	Positive real functions: Concept of positive real function, testing for Hurwitz polynomials, testing for necessary and sufficient conditions for positive real functions	
	3.2	Synthesis of RC, RL, LC circuits: Concepts of synthesis of RC, RL, LC driving point functions (numerical problems not expected on 3.2)	
4.0		Two Port Networks	08
	4.1	Parameters: Open Circuit, Short Circuit, Transmission and Hybrid parameters, relationships among parameters, reciprocity and symmetry conditions	
	4.2	Series/parallel connection: T and Pi representations, interconnection of Two-Port networks,	
5.0		Flirters and attenuators	08
	5.1	Basic filter circuits: Low pass, high pass, band pass and band stop filters, transfer function, frequency response, cutoff frequency, bandwidth, quality factor, attenuation constant, phase shift, characteristic impedance	
	5.2	Concept of design and analysis of filters: Constant K, M derived and composite filters (numerical problems not expected on 5.2)	
	5.3	Attenuators: Basic concepts, classification, attenuation in dB, K factor (impedance factor) and design concepts (numerical problems not expected on 5.3)	
6.0		Transmission Lines	09
	6.1	Power frequency lines: Representation, losses and efficiency in power lines, effect of length, calculation of inductance and capacitance (numerical problems not expected)	
	6.2	Radio frequency lines: Representation, propagation constant, attenuation constant, phase constant, group velocity, input impedance, characteristic impedance, reflection coefficient, standing wave ratio, VSWR, ISWR, S-parameters	
	6.3	Smith Chart: Impedance locus diagram, impedance matching	
		Total	52

Recommended Books:

- 1. Franklin F Kuo, "Network Analysis and Synthesis", Wiley Toppan,
- 2. M E Van Valkenburg, "Network Analysis", Prentice-Hall of India Pvt Ltd, New Delhi
- 3. K V V Murty and M S Kamth, "Basic Circuit Analysis", Jaico Publishing house, London
- 4. A. Chakrabarti, "Circuit Theory", Dhanpat Rai and Co., New Delhi
- 5. Reinhold Ludwig and Pavel Bretchko, "RF Circuit Design", Pearson Education, Asia
- 6. Joseph J. Carr, "Secrets of RF Circuit Design", Tata McGraw-Hill, New Delhi

Internal Assessment (IA):

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- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Te	eaching Sche	me	Credits Assigned					
		Theory	Practical	Tutorial	Theory	TW/	Tutorial	Total		
						Practical				
EXC 305	Electronic	04			04			04		
	Instruments									
	and									
	Measurements									

Subject	Subject Name		Examination Scheme								
Code			Th	eory Marks	5	Term	Practical	Oral	Total		
		Inte	rnal ass	sessment	End Sem.	Work					
		Test	Test	Ave. Of	Exam						
		1	2	Test 1							
				and Test							
				2							
EXC305	Electronic	20	20	20	80		-		100		
	Instruments and										
	Measurements										

Prerequisite Topics:

System of units, Measuring Instrument.

Course Objective:

Objectives of this course are:

- 1. In depth knowledge of measurement methods and instruments of electrical quantities.
- 2. Understanding design aspects and performance criterion for measuring instruments.
- 3. Implementation of the different signal generators and its analysis techniques.
- 4. To understand the working principle of the transducers.
- 5. To aware the students about the advances in Instrumentation.

Course Outcomes:

The outcomes of this course are:

- 1. An ability to apply knowledge of electronic instrumentation for measurement of electrical quantities.
- 2. Ability to apply the principles and practices for instrument design and development to real world problems.
- 3. Ability to select and use latest hardware for measurements and instrumentation.
- 4. An ability to design and conduct experiments for measurement and ability to analyze and interprets data.

Module No	Topics	Hrs.
No 1.	Principles of Measurement	06
1.	1.1 Introduction to Basic Instruments: Components of Generalized measurement	00
	system, applications of instrument systems, static and dynamic characteristics of	
	instruments, Concepts of Accuracy, Precision, Linearity, Sensitivity, Resolution,	
	Hysteresis, Calibration etc.	
	1.2 Errors in Measurement: Errors in Measurement, Classification of Errors, Remedies	
	to Eliminate/Reduce Errors.	
2	Test and Measuring Instruments	10
	2.1 Analog Multi-meters: Multi-range, Multi-parameter Measurement, Electronics	
	Voltmeter using Transistors, FETs and Opamps. Specifications of a multi-meter.	
	2.2 RLC and Q-meter: Measurement of Low, Medium and High Resistance using	
	Wheatstone bridge, Kelvin's Double Bridge and Mega ohm Bridge; Measurement of	
	Inductance using Maxwell Bridge and Hey Bridge; Measurement of Capacitance using	
	Schering Bridge; Operating Principle and Applications of Q-Meter.	
	2.3 Digital Multi-meters: DMM; Automation, Auto Ranging and Auto Zero Adjustments	
	in Digital Instruments.	
3	Oscilloscopes	10
	3.1 Cathode Ray Oscilloscope: Block Diagram based Study of CRO, Specifications,	
	Controls, Sweep Modes, Role of Delay Line, Single- and Dual-Beam Dual-Trace CROs,	
	Chop and Alternate Modes.	
	3.2 Measurement using Oscilloscope: Measurement of Voltage, Frequency, Rise Time,	
	Fall Time and Phase Difference. Lissajous Figures in Detection of Frequency and Phase.	
	3.3 Digital Storage Oscilloscope (DSO): Features like Roll, Refresh, Storage Mode and	
4	Sampling Rate; Applications of DSO.	0.0
4	Transducers for Displacement and Temperature Measurement	08
	4.1 Basics of Transducers/Sensors : Characteristics of Transducers; Requirement of Transducers; Classification of transducers; Selection Criteria of Transducers;	
	Transducers; Classification of transducers; Selection Criteria of Transducers.	
	4.2 Displacement: Potentiometers; Linear Variable Differential Transformer, Resistance Strain Gauges, Capacitance Sensors.	
	4.3 Temperature: RTD, Thermisters, Thermocouples- Their Ranges, and Applications.	
5	Transducers for Pressure, Level and Flow Measurement	10
5	5.1 Pressure: Pressure gauges; Elastic Pressure Transducers; Dead Weight Tester;	10
	Vacuum Pressure Measurement- McLeod Gauge and Pirani Gauge.	
	5.2 Level: Side glass tube method; Float type methods; Capacitance type method;	
	Ultrasonic type transducer.	
	5.3 Flow: Restriction type Flow meters-Orifice and Venturi; Rotameter; Magnetic Flow	
	meter; Turbine Flow meter.	
6	Data Acquisition and advances in Instrumentation Systems	08
-	6.1 Monitoring Instruments : Indicators, Alarm, Recorders.	
	6.2 Data Acquisition and Converters: Data logger; Data acquisition system (DAS)-	
	Single channel, Multichannel.	
	6.3 PC based Instrumentation: PC based Instrumentation System; Introduction to	
	Programmable Logic Controller.	
	Total	52

Rcommended Books:

- 1. H. Oliver and J. M. Cage, Electronic Measurement and Instrumentation, McGraw Hill, 3rd edition.
- 2. W. Cooper, A. Helfric, Electronic Instrumentation and Measurement Techniques, PHI, 4th edition.
- **3.** C. S. Rangan, G.R. Sarma, V.S.V. Mani, Instrumentation Devices and Systems, Tata McGraw Hill, 9th edition.
- **4.** A. K. Sawhney, Electrical & Electronic Instruments & Measurement, Dhanpat Rai and Sons, Eleventh ed., 2000.
- **5.** Dally, William F. Riley and Kenneth G, Instrumentation for Engineering Measurements, James John Wiley and Sons. Inc., 2nd Edition 1993.
- 6. A.J. Bowens, Digital Instrumentation, McGraw-Hill, latest addition.
- 7. J.J.Carr, Elements of Electronic Instrumentation and Control, Prentice Hall, 3rd edition.

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

SE Electronics Engineering Semester III Syllabus of Laboratory

Subject Code	Subject Name	Teach	ning Scheme	;	Credits Assigned				
		Theory	Practical	Theory	TW/Pract.	Tut.	Total		
EXL301	Electronic Devices Laboratory	02 -				01	-	01	

	Subject Name	Examination Scheme							
Sub.		Theory	Marks			TW	Pract and	Oral	Total
Code		Internal	Internal Assessment End						
EXL301	Electronic Devices	Test 1	Test 2	Average of Test1 & Test2	Semester Exam				
	Laboratory					25	50		75

Syllabus: Same as that of Subject EXC 302 Electronic Devices

Term Work:

At least 10 experiments covering entire syllabus of EXC 302 (Electronic Devices) should be set to have well predefined inference and conclusion. Computation/simulation based experiments are encouraged. Therefore at least 5 simulation experiments to be carried out (out of total 10 Expts.). The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades should be converted into marks as per the Credit and Grading System manual and should be added and averaged. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Guidelines for Simulation Experiments:

- 1. One SPICE simulations and implementation for junction analysis
- 2. One SPICE simulation and implementation for BJT characteristics
- 3. One SPICE simulation and implementation for JFET characteristics
- 4. One SPICE simulation and implementation for Optical devices
- 5. One SPICE simulation and implementation for power devices
- 6. One SPICE simulation for MOSFET characteristics

Subject Code	Subject Name	Те	aching Sch	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total	
EXL 302	Digital		02			01		01	
	Circuits and								
	Design								
	Laboratory								

Subject	Subject			J	Examination S	Scheme					
Code	Name		1	Theory Marks		Term	Practical	Oral	Total		
		Int	ernal a	ssessment	End Sem.	Work	and				
		Test	Test	Ave. Of Test	Exam		Oral				
		1	2	1 and Test 2							
EXL 302	Digital					25	50	-	75		
	Circuits and										
	Design										
	Laboratory										

Syllabus: Same as EXC 303 (Digital Circuits and Design)

Term Work:

At least 10 experiments covering entire syllabus of EXC 303 (Digital Circuits and Design) should be set to have well predefined inference and conclusion. Computation/simulation based experiments are encouraged. Therefore, 5 simulation experiments be carried out (out of total 10 Expts.). The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades should be converted into marks as per the Credit and Grading System manual and should be added and averaged. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Suggested Experiments:

- 1. SOP and POS Minimization (different problem statement for each student)
- 2. Characteristics of TTL and MOS logic family
- 3. Implementation of combinational circuits using MSI devices. (at least two)
- 4. Implementation of counters with flip-flops (at least one synchronous and one asynchronous)
- 5. Implementation of sequential circuits using MSI devices. (at least two)
- 6. Implementation of FSM (different problem statement for each student)
- 7. VHDL based simulations (Instructor should teach syntax and give different program to each student for simulation. Minimum Four programs covering behavioral, structural and dataflow modeling)
- 8. Verilog/VHDL based simulations (Instructor should teach syntax and give different program to each student for simulation. Minimum Four programs covering behavioral, structural, dataflow and switch level modeling)
- 9. Synthesis, downloading and Verification on CPLD and FPGA (for both VHDL and Verilog programs)

10. Troubleshooting of given fault (teacher should generate set of faults in different circuits and ask students to troubleshoot)

Subject Code	Subject Name	Г	eaching Sche	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total	
EXL 303	Circuit Theory and Measurements Laboratory		02			01		01	

Subject	Subject Name		Examination Scheme							
Code			,	Theory Marks		Term	Practical	Oral	Total	
		Int	ternal a	ssessment	End Sem.	Work	and			
		Test	Test	Ave. Of Test	Exam		Oral			
		1	2	1 and Test 2						
EXL	Circuit Theory and					25			25	
303	Measurements									
	Laboratory									

Syllabus: EXC 304 (Circuit Theory) and

EXC 305 (Electronic Instruments and Measurements)

05 Experiments Each

Term Work:

At least 05 experiments on of EXC 304 (Circuit Theory) and 05 experiments on EXC 305 (Electronic Instruments and Measurements) based on the entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades should be converted into marks as per the Credit and Grading System manual and should be added and averaged. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned				
		Theory	Practical	Tutorial	Theory	Term Work and Pract.	Tutorial	Total	
EXL 304	*Object Oriented Programming Methodology Laboratory		02+02**			02		02	

Subject	Subject Name		Examination Scheme								
Code			,	Theory Marks		Term	Practical	Oral	Total		
		Internal assessment			End Sem.	Work	and				
		Test	Test	Ave. Of Test	Exam		Oral				
		1	2	1 and Test 2							
EXL 304	*Object					25	50	-	75		
	Oriented										
	Programming										
	Methodology										
	Laboratory										

** 02 Hours be converted to theory hours for entire class theory discussion

Pre-requites: Course in Structured Programming Approach/ Any Programming Language

Course Objectives:

- 1. To understand the concept of Object Oriented Programming
- 2. To help student to understand how to use a programming language such as JAVA to resolve problems.
- 3. To impart problems understanding, analyzing skills in order to formulate Algorithms.
- 4. To provide knowledge about JAVA fundamentals: data types, variables, keywords and control structures.
- 5. To understand methods, arrays, inheritance, Interface, package and multithreading.
- 6. To understand the concept of Applet.

- 1. Students will be able to code a program using JAVA constructs.
- 2. Given an algorithm a student will be able to formulate a program that correctly implements the algorithm.
- 3. Students will be able to generate different patterns and flows using control structures.
- 4. Students will be able to make use of recursion in their programs.
- 5. Students will be able to use thread methods, thread exceptions and thread priority.
- 6. Students will implement method overloading in their code.
- 7. Students will be able to demonstrate reusability with the help of inheritance.
- 8. Students will be able to make more efficient programs.

Module	Unit	Торіс	Hrs.
No.	No.		
1		Fundamental concepts of object oriented programming	4
	1.1	Overview of Programming	
	1.2	Introduction to the principles of object-oriented programming : Classes,	
		Objects, Messages, Abstraction, Encapsulation, Inheritance,	
		Polymorphism, exception handling, and object-oriented containers	
	1.3	Differences and Similarity between C++ and JAVA	
2		Fundamental of Java Programming	4
	2.1	Features of Java	
	2.2	JDK Environment & tools	
	2.3	Structure of java program	
	2.4	Keywords, Data types, Variables, Operators, Expressions	
	2.5	Decision Making, Looping, Type Casting	
	2.6	Input output using scanner class	
3		Classes and Objects	6
	3.1	Creating Classes and objects	
	3.2	Memory allocation for objects	
	3.3	Passing parameters to Methods	
	3.4	Returning parameters	
	3.5	Method overloading	
	3.6	Constructor and finalize()	
	3.7	Arrays : Creating an array	
	3.8	Types of Array : One Dimensional arrays, Two Dimensional array	
4		Inheritance, Interface and Package	6
	4.1	Types of Inheritance : Single ,Multilevel, Hierarchical	
	4.2	Method Overriding, Super keyword, Final Keyword, Abstract Class	
	4.3	Interface	
	4.4	Packages	
5		Multithreading	4
	5.1	Life cycle of thread	
	5.2	Methods	
	5.3	Priority in multithreading	
6		Applet	2
	6.1	Applet Life cycle	
	6.2	Creating applet	
	6.3	Applet tag	
		Total	26

Term Work:

At least 10 experiments covering entire syllabus should be set to have well predefined inference and conclusion. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every experiment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Sub Code	Subject Name	Teach	ing Schem	e(Hrs.)		Credits As	signed	
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
EXS 401	*Applied Mathematics IV	04		01	04		01	05
EXC402	Discrete Electronic Circuits	04			04			04
EXC 403	Microprocessor and	04			04			04
	Peripherals							
EXC404	Principles of Control	04			04			04
	Systems							
EXC405	Fundamentals of	04			04			04
	Communication Engineering							
EXC406	Electrical Machines	03			03			03
EXL401	Discrete Electronics		02			01		01
	Laboratory							
EXL402	Microprocessor and		02			01		01
	Peripherals Laboratory							
EXL403	Control System and		02			01		01
	Electrical Machines							
	Laboratory							
EXL 404	Communication Engineering		02			01		01
	Laboratory							
Total		23	08	01	23	04	01	28

Subject	Subject Name			Exam	ination S	cheme			
Code			Th	eory Marks		Term	Practi	Oral	Total
					-	Work	cal		
		I	nternal a	ssessment	End		and		
		Test	Test 2	Ave. of Test	Sem.		Oral		
		1		1 and Test 2	Exam				
EXS 401	*Applied Mathematics IV	20	20	20	80	**25			125
EXC402	Discrete Electronic Circuits	20	20	20	80				100
EXC 403	Microprocessor and	20	20	20	80				100
	Peripherals								
EXC404	Principles of Control	20	20	20	80				100
	Systems								
EXC405	Fundamentals of	20	20	20	80				100
	Communication								
	Engineering								
EXC406	Electrical Machines	15	15	15	60				75
EXL 401	Discrete Electronics					25	50		75
	Laboratory								
EXL 402	Microprocessor and					25		25	50
	Peripherals Laboratory								
EXL 403	Control Systems and					25		25	50
	Electrical Machines								
	Laboratory								
EXL 404	Communication					25	50		75
	Engineering Laboratory								
Total				115	460	125	100	50	850

*Subject Common with EXTC, Electrical Engg, Instrumentation Engg, Biomedical Engg.

** Tutorial work will be assessed as Term Work

SE Electronics Engineering Semester IV Syllabus of Theory Subjects

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
EXS 401	Applied Mathematics IV	04		01	04		01	05

Subject	Subject Name		Examination Scheme							
Code]	Theory Marks		Tutorial	Practic	Oral	Total	
		Internal assessment End Sem.			End Sem.	as Term	al			
		Test	Test	Ave. Of	Exam	Work				
		1	2	Test 1 and						
				Test 2						
EXS401	Applied	20	20	20	80	25			125	
	Mathematics IV									

Course Prerequisite: Applied Mathematics III

Course Objective:

This course will present the method of calculus of variations (CoV), basic concepts of vector spaces, matrix theory, concept of ROC and residue theory with applications.

Expected Outcome:

Students in this course will apply the method of CoV to specific systems, demonstrate ability to manipulate matrices and compute eigenvalues and eigenvectors, Identify and classify zeros, singular points, residues and their applications. After completion of this course students will be:

Module	Unit	Topics	Hrs.
No.	No.		
1.0	1.0	Calculus of variation	10
	1.1	a. Euler's Langrange equation, solution of Euler's Langrange equation	
		(only results for different cases for function) independent of a variable,	
		independent of another variable, independent of differentiation of a variable and	
		independent of both variables	
	1.2	b. Isoperimetric problems, several dependent variables	
	1.3	Functions involving higher order derivatives: Rayleigh-Ritz method	
2.0	2.0	Linear Algebra: Vector spaces	12
	2.1	Vectors in n-dimensional vector space: properties, dot product, norm and	
		distance properties in n-dimensional vector space.	
	2.2	Metric spaces, vector spaces over real field, properties of vector spaces over real	
		field, subspaces.	
	2.3	Norms and normed vector spaces	
	2.4	Inner products and inner product spaces	
	2.5	The Cauchy-Schwarz inequality, Orthogonal Subspaces, Gram-Schmidt process	
3.0	3.0	Linear Algebra: Matrix Theory	15
	3.1	Characteristic equation, Eigen values and Eigen vectors, properties of Eigen	
		values and Eigen vectors	
	3.2	Cayley-Hamilton theorem, examples based on verification of Cayley-Hamilton	
		theorem	
	3.3	Similarity of matrices, Diagonalisation of matrix	
	3.4	Functions of square matrix, derogatory and non-derogatory matrices	
	3.5	Quadratic forms over real field, reduction of Quadratic form to a diagonal	
		canonical form, rank, index, signature of quadratic form, Sylvester's law of	
		inertia, value-class of a quadratic form of definite, semi- definite and indefinite	
	3.6	Singular Value Decomposition	
4.0	4.0	Complex Variables: Integration	15
	4.1	Complex Integration: Line Integral, Cauchy's Integral theorem for simply	
		connected regions, Cauchy's Integral formula	
	4.2	Taylor's and Laurent's series	
	4.3	Zeros, singularities, poles of f(z), residues, Cauchy's Residue theorem	
	4.4	Applications of Residue theorem to evaluate real Integrals of	
		$\int f(\sin\theta,\cos\theta)d\theta \text{and} \int f(x)dx$	
			50
		Total	52

Recommended books:

- 1. *A Text Book of Applied Mathematics* Vol. I & II by P.N.Wartilar & J.N.Wartikar, Pune, Vidyarthi Griha Prakashan., Pune
- 2. Mathematical Methods in science and Engineering, A Datta (2012)
- 3. Higher Engg. Mathematics by Dr. B.S. Grewal, Khanna Publication
- 4. Todd K.Moon and Wynn C. Stirling, *Mathematical Methods and algorithms for Signal Processing*, Pearson Education..
- 5. Kreyszig E., Advanced Engineering Mathematics, 9th edition, John Wiley, 2006.
- 6. *Linear Algebra* Hoffman & Kunze (Indian editions) 2002

- 7. Linear Algebra Anton & Torres(2012) 9th Indian Edition.
- 8. *Complex Analysis* Schaum Series.

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

End Semester Examination:

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining questions (Q.2 to Q.6) will be set on all the modules.
- 5: Weightage of marks will be as per Blueprint.

Term Work:

At least **08** assignments covering entire syllabus must be given during the **Class Wise Tutorial.** The assignments should be students' centric and an attempt should be made to make assignments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every assignment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

Subject Code	Subject Name	Teacl	ning Scheme	Credits Assigned				
		Theory	Pract.	Tut.	Theory	TW/Pract.	Tut.	Total
EXC 402	Discrete Electronic Circuits	04		-	04		-	04

	Subject Name	Examina	ation Sche	eme					
		Theory MarksTWPract.							Total
Sub. Code		Internal Assessment			End				
EXC 402	Discrete Electronic	Test 1	Test 2	Average of Test1 & Test2	Semester Exam				
	Circuits	20	20	20	80				100

Prerequisite: FEC105 Basic Electrical & Electronics Engineering and EXC 302 Electronic Devices Course Objectives:

- 1. To understand DC biasing needed for various applications.
- 2. To understand DC and AC models of semiconductor devices and usefulness of the devices for various applications like amplifiers, oscillators etc..
- 3. To apply concepts of DC and AC modeling of semiconductor devices for the design and analysis.
- 4. To understand theoretical concepts and verify through laboratory and simulation experiments.
- 5. To deliver the core concepts and reinforce the analytical skills learned in Electronic Devices
- 6. To motivate students to use MOS devices for designing and analyzing electronic circuits which will help them to understand the fundamentals required for further part of Engineering

- 1. Students will be able to understand and the usefulness of semiconductor devices in circuit making.
- 2. Students will be Able to perform dc and ac analysis of the basic electronic circuits useful to conclude an application based on these.
- 3. They will be able to analyze and design multistage electronic circuits.
- 4. Mainly understanding of discrete and integrated biasing will be understood and very useful for mixed mode designs..
- 5. They will understand the difference between small signal and large signal amplifiers.
- 6. They will be able to use these basic circuits to develop various useful applications.

Module No. Topics							
1.0	Bipolar device based circuit analysis	08					
1.1	Review of Diode Based circuits: Analytical analysis of Single level clippers, Double						
	level Clippers and clampers (both only explanation, no analytical analysis)						
1.2	DC Circuit Analysis of BJT: DC load line and region of Operation, Common Bipolar						
	Transistor Configurations, Single base resistor biasing, voltage divider biasing and bias						
	stability, Analysis and Design of biasing circuits						
1.3	AC Analysis of BJT Amplifiers: Bipolar Junction Transistor (BJT): Graphical						
	Analysis and AC Equivalents Circuits, Small Signal hybrid-pi model (no other models),						
	early effect, Common-Emitter Amplifiers, Common-Collector Amplifiers, Common-Base						
	Amplifiers.						
2	Field Effect devices based sincuit analysis	10					
	Field Effect devices based circuit analysis	10					
2.1	DC Circuit Analysis:						
	Junction Field Effect Transistor (JFET): Self bias, Voltage divider bias, Design and Analysis of Biasing Circuits						
	Metal-Oxide Field Effect Transistor (MOSFET): Common-Source circuits, DC load						
	line and region of operation, Common-MOSFETS configurations, Analysis and Design of						
	Biasing Circuits						
2.2	AC Analysis:						
	JFET Amplifiers: Small-Signal Equivalent Circuit, Small-Signal Analysis						
	MOSFET Amplifiers: Graphical Analysis, load line and Small-Signal parameters, AC						
	Equivalent Circuit, Small-Signal Model. Common-Source, Source Follower, Common-						
	Gate						
3.0	Multistage analysis and Frequency Analysis of Amplifiers	10					
3.1	Multistage (CS-CS), (CS-CE) cascode (CS-CG) Amplifiers & Darlington pair.						
3.2	Effect of capacitors (coupling, bypass, load) on frequency response of JFET and						
	MOSFET Amplifiers, High frequency hybrid-pi equivalent circuits of MOSFET, Miller						
	Effect and Miller capacitance, unity gain bandwidth, Low and high frequency response of						
	single stage (CS,CG, CD) and multistage (CS-CS).						
4.0	Faadhaalt Amalifians and Ozaillatans	08					
	Feedback Amplifiers and Oscillators	00					
4.1	Types of Negative Feedback, block diagram representation, Effect of negative feedback on						
	Input impedance, Output impedance, Gain and Bandwidth with derivation, feedback						
	topologies (analysis of different feedback circuits is not expected).						
4.2	Positive feedback and principle of oscillations, RC oscillators: Phase shift (no derivations),						
	Wien bridge, LC Oscillators: Hartley, Colpitts and clapp, Tunned Oscillator (no derivations),						
	Twin T Oscillator (no derivations), Crystal Oscillator (BJT circuits analysis).						
5.0	Differential Amplifiers	10					

5.1	BJT Differential Amplifier: Terminology and qualitative description, DC transfer characteristics, Small signal Analysis, differential and common mode gain, CMRR, differential and common mode input impedance.	
5.2	MOSFET Differential Amplifiers: DC Transfer characteristics, Small signal Analysis, differential and common mode gain, CMRR, differential and common mode input impedance.	
5.3	Constant Current Sources: Two transistor (BJT, MOSFET) current source, current relationship, output resistance. Improved three transistor (BJT, MOSFET) current source, Cascode (BJT, MOSFET) current source, Wilson and Widlar current source	
6.0	Power Amplifiers	06
6.1	Power BJTs, Power MOSFETs, Heat Sinks, Class A, Class B, Class C and Class AB operation, Power efficiency, Class AB output stage with diode biasing, VBE multiplier biasing, input buffer transistors, Darlington configuration.	
	Total	52

Recommended Books:

- 1. Donald A. Neamen, "Electronic Circuit Analysis and Design", TATA McGraw Hill, 2nd Edition
- 2. Adel S. Sedra, Kenneth C. Smith and Arun N Chandorkar," Microelectronic Circuits Theory and
- Applications", International Version, OXFORD International Students Edition, Fifth Edition.
- 3. David A. Bell, "Electronic Devices and Circuits", Oxford, Fifth Edition.
- 4. S. Salivahanan, N. Suresh Kumar, *"Electronic Devices and Circuits"*, Tata McGraw Hill, 3rd Edition
- 5. Jacob Millman, Christos C Halkias, and Satyabratata TIT, "Millman's Electronic Devices and Circuits", McGrawHill, 3rd Edition
- 6. Muhammad H. Rashid, "*Microelectronics Circuits Analysis and Design*", Cengage Learning, 2nd Edition
- 7. Jacob Millman and Arvin Grabel, "Mircroelectronics", Tata McGraw-Hill Second Edition

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Te	aching Sche	eme		Credit	ts Assigned	
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total
EXC 403	Microprocessor and Peripherals	04			04			04

Subject	Subject Name	Examination Scheme							
Code			T	heory Marks		Term	Practical	Oral	Total
		Int	ternal a	ssessment	End	Work	and		
		Test	Test	Ave. Of Test	Sem.		Oral		
		1	2	1 and Test 2	Exam				
EXC 403	Microprocessor and	20	20	20	80			-	100
	Peripherals								

Course Objective:

To create a strong foundation by studying the basics of Microprocessors and interfacing to various peripherals which will lead to a well designed Microprocessor based System. The course is a pre-requisite for all further courses in Microcontrollers and Embedded systems.

- 1. Students will be able to understand and design Microprocessor based systems.
- 2. Students will be able to understand assembly language programming
- 3. Students will be able to learn and understand concept of interfacing of peripheral devices and their applications

Module No.	Topics	Hrs.					
	Introduction to Intel 8085 Microprocessor: Basic functions of the						
1	microprocessor, System bus, Architecture, Pin Configuration and	06					
	Programmer's model of Intel 8085 Microprocessor.						
2	Intel 8086 Architecture: Major features of 8086 processor, 8086/88						
	CPU Architecture and the pipelined operation, Programmer's Model	06					
	and Memory Segmentation						
	Instruction Set of 8086 and Programming: Instruction Set of						
	8086 microprocessor in details, Addressing modes of 8086/88,						
3	Programming the 8086 in assembly language, Mixed mode	10					
	Programming with C-language and assembly language. Assembler						
	Directives Procedures and Macros.						
4	8086 Interrupts: Interrupt types in 8086, Dedicated interrupts, Software	04					
	interrupts,	04					
	Designing the 8086 CPU module: 8086 pin description in details, Generating the 8086 System Clock and Reset Signals, 8086						
5							
5	Minimum and Maximum Mode CPU Modules, Memory interfacing with	10					
	timing consideration, Minimum and Maximum Mode Timing Diagrams						
	Peripheral Controllers for 8086 family and System Design:						
	Functional Block Diagram and description, Control Word Formats,						
6	Operating Modes and Applications of the Peripheral Controller	08					
0	namely 8255-PPI, , 8259- PIC and 8237-DMAC.	08					
	Interfacing of the above Peripheral Controllers. Keyword and						
	Display Interface using 8255.						
	Multiprocessor Systems:						
7	Study of Multiprocessor Configurations namely Closely Coupled						
	System (CCS) and Loosely Coupled System (LCS), CCS with the						
	case study of the Maths Coprocessor, Various System Bus Arbitration						
	Schemes in LCS, and Role of the Bus Arbiter (Intel 8289) in the LCS.						
	Total	52					

Recommended Books:

1) Microprocessor architecture and applications with 8085: By Ramesh Gaonkar (Penram International Publication).

- 2) 8086/8088 family: Design Programming and Interfacing: By John Uffenbeck (Pearson Education).
- 3) 8086 Microprocessor Programming and Interfacing the PC: By Kenneth Ayala

4) Microcomputer Systems: 8086/8088 family Architecture, Programming and Design: ByLiu & Gibson (PHI Publication).

5) Microprocessor and Interfacing: By Douglas Hall (TMH Publication).

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Te	eaching Sche	eme	Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
EXC 404	Principles of Control Systems	04			04			04

Subject	Subject Name	Examination Scheme							
Code		Theory Marks				Term	Practical	Oral	Total
		Internal assessment			End	Work			
		Test	Test	Ave. Of	Sem.				
		1	2	Test 1 and	Exam				
				Test 2					
EXC	Principles of	20	20	20	80		-		100
404	Control Systems								

Prerequisite Topics:

Differential equations; Laplace transforms and Matrices.

Course Objectives:

Objectives of this course are:

- 1. To study the fundamental concepts of Control systems and mathematical modeling of the system.
- 2. To study the concept of time response and frequency response of the system.
- 3. To study the basics of stability analysis of the system and design of simple controllers

- 1. Students will be able to derive the mathematical model of different type of the systems.
- 2. Students will understand the basic concepts of control system.
- 3. Students will understand the analysis of systems in time and frequency domain.
- 4. Students will be able to apply the control theory to design the conventional PID controller widely used in the industries.

Module No.	Topics	Hrs.
	Introduction to control system analysis	
	1.1 Introduction: Open loop and closed loop systems; feedback and	
	feedforward control structure; examples of control systems.	
1.	1.2 Modeling: Types of models; Impulse response model; State variable model;	06
1.	Transfer function model.	06
	1.3 Dynamic Response: Standard test signals; Transient and steady state	
	behavior of first and second order systems; Steady state errors in feedback	
	control systems and their types.	
	Mathematical modeling of systems	
	2.1 Transfer function models of various systems: Models of mechanical	
2	systems; Models of electrical systems; Models of thermal systems.	08
	2.2 Manipulations: Block diagram reduction; Signal flow graph and the	
	Mason's gain rule.	
	State Variable Models	
	3.1 State variable models of various systems: State variable models of	
	mechanical systems; State variable models of electrical systems; State variable	
	models of thermal systems.	
3	3.2 State transition equation: Concept of state transition matrix; Properties of	12
U	state transition matrix; Solution of homogeneous systems; solution of non-	
	homogeneous systems.	
	3.3 Controllability and observability: Concept of controllability;	
	Controllability analysis of LTI systems; Concept of observability; Observability	
	analysis of LTI systems using Kalman approach.	
	Stability analysis in time domain	
4	4.1 Concepts of Stability: Concept of absolute, relative and robust stability;	06
4	Routh stability criterion.	06
	4.2 Root locus analysis: Root-locus concepts; General rules for constructing	
	root-locus; Root-locus analysis of control systems.	
	Stability analysis in frequency domain5.1 Introduction: Frequency domain specifications, Response peak and peak	
	resonating frequency; Relationship between time and frequency domain	
	specification of system; Stability margins.	
5	5.2 Bode plot: Magnitude and phase plot; Method of plotting Bode plot;	10
	Stability margins on the Bode plots; Stability analysis using Bode plot.	
	5.3 Nyquist Criterion: Polar plots, Nyquist stability criterions; Nyquist plot;	
	Gain and phase margins.	
	Compensators and controllers	
	6.1 Compensators: Types of compensation; Need of compensation; Lag	
	compensator; Lead compensator.	10
6	6.2 Controllers: Concept of ON/OFF controllers; Concept of P, PI, PD and	- •
0	PID Controllers.	
	6.3 Advances in Control Systems: Introduction to Robust Control, Adaptive	
	control and Model predictive control.	
	Total	<mark>52</mark>

Recommended Books

- 1. I. J. Nagrath, M. Gopal, Control Systems Engineering, New Age International, Fifth Edition, 2012.
- 2 Dhanesh N. Manik, Control Systems, Cengage Learning, First Edition, 2012.
- 3. M. Gopal, Control Systems: Principle and design, Tata McGraw Hill, First Edition, 1998
- 4. Richard C. Dorf and Robert H. Bishop, Modern Control System, Pearson, Eleventh Edition, 2013.
- 5. Norman S. Nice, Control Systems Engineering, John Wiley and Sons, Fifth Edition, 2010
- 6. Rajeev Gupta, Control Systems Engineering, Wiley India, First Edition, 2011.

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

End Semester Examination:

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be set from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Te	eaching Sche	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total	
EXC	Fundamentals of	04			04			04	
405	Communication								
	Engineering								

Subject	Subject Name		Examination Scheme								
Code			r	Theory Marks		Term	Practical	Oral	Total		
		In	ternal a	assessment	End Sem.	Work	And Oral				
		Tes Test Ave. Of			Exam						
		t1 2 Test 1 and									
				Test 2							
EXC	Fundamentals of	20	20	20	80				100		
405	Communication										
	Engineering										

Prerequisite Topics: Basic Electronic Devices and Circuits and measurements

Course Objective:

- 1. To understand basics of wireless communication systems.
- 2. To understand modulation and demodulation techniques.
- 3. To understand working of transmitters and receivers
- 4. To understand the basic concept of Digital communication

Course Outcome:

- **1.** Students will be able to understand the components of wireless communication systems
- 2. Students will be able to understand various modulation techniques and their applications
- 3. Students will be able to understand difference between analog and digital communication

Module No.	Unit No.	Topics	Hrs.
1.0		Elements of Communication System :	08
	1.1	Electromagnetic Waves Propagation: Maxwell's equations for static and time	
		varying fields, wave equation for free space and dielectric mediums, propagation	
		terms and definition, electromagnetic frequency spectrum,	
	1.2	Basic communication system: Block diagram representation	
	1.3	Concept of Modulation and Demodulation: Signal representation, noise in	
		communication signals and channels, signal-to-noise ratio, noise factor and noise	
		figure, equivalent noise temperature	
2.0		Amplitude Modulation	10
	2.1	Principles of DSB Full Carrier AM	
	2.2	Different types of AM : DSB-SC ,SSB-SC , VSB, ISB	
	2.3	Practical diode detector	
3.0		Angle modulation	10
	3.1	Principles of Frequency Modulation and Phase Modulation	
	3.2	FM Modulators: Narrow band FM and wide band FM, FM transmitter, noise	
		triangle, Pre-emphasis and De-emphasis circuits	
	3.3	FM Detection: frequency discriminator and phase discriminator	
4.0		Radio Receivers	06
	4.1	Receiver Characteristics, TRF Receivers, and Super heterodyne, Receivers,	
		Choice of IF, AGC, AFC in AM and FM receivers	
5.0		Analog Pulse Modulation	08
	5.1	Sampling: Theorem, aliasing error and sampling techniques	
	5.2	Demodulation and spectrum of PAM, PWM, PPM	
6.0		Digital Pulse Modulation(only concepts and no numerical problems)	10
	6.1	Comparison of digital signal transmission and analog signal transmission	
	6.2	Pulse- code modulation (PCM) : sampling ,quantizing ,encoding technique, PCM bandwidth	
	6.3	Concept of Delta modulation (DM) and Adaptive Delta Modulation(ADM)	
	6.4	Multiplexing: TDM, FDM- Principles & applications	
		Total	52

Recommended Books:

- 1. Wayne Tomasi "Electronics communication systems" Pearson education, Third edition, 2001.
- 2. Kennedy and Davis "Electronics communication system", Tata McGraw Hill
- 3. R.P. Sing and S.D. Sapre, "Communication systems Analog and Digital", Tata McGraw Hill
- 4. Taub and Schilling "Principles of communication systems", Tata McGraw Hill
- 5. Roy Blake, "Electronics communication system", Thomson learning, second edition.
- 6. B.P. Lathi "Modern Digital and analog Communication system" Third edition, OXFORD
- 7. Robert J. Schoenbeck "Electronics communications modulation and transmission".
- 8. Lean W couch "Digital and Analog communication system", Pearson education, Sixth edition.
- 9. Roddy Coolen, "Electronic Communications" PHI

Term Work<mark>:</mark>

At least 10 experiments based on the entire syllabus should be set to have well predefined inference and conclusion. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every experiment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

End Semester Examination:

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teach	ning Schem	e (Hrs)	Credits Assigned				
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total	
EXC 406	Electrical	3			3			03	
	Machines								

Subject	Subject Name			E	xamination S	Scheme				
Code			Т	heory Marks		Term	Practical	Oral	Total	
		Inte	rnal as	sessment	End Sem.	Work				
		Test 1 Test Ave. Of Exam								
			2 Test 1 and							
				Test 2						
EXC 406	Electrical	15	15	15	60		-	-	75	
	Machines									

Course Objective: To understand performance, working of Electrical Machines and their characteristics etc.

Expected Outcome:

- 5. Students will be able to understand electrical motors and their working principles
- 6. Students will be able to understand brushless drives
- 7. Students will be able to understand special types of motors such as stepper motor and applications

Module No.	Unit No.	Contents	Hrs.
1.0		DC Machines	08
	1.1	Construction: principle of working, MMF and flux density waveforms, significance of commutator and brushes in DC machine,	
	1.2	EMF equation : and Torque equation, characteristics of DC Motors,	
	1.3	Starters for shunt and series motors	
	1.4	Speed Control (Armature voltage control and field control using block diagrams)	
2.0		Three phase Induction Motor	08
	2.1	Construction : Working principle of squirrel cage induction motor,	
	2.2	Equivalent circuit : Equivalent circuit development, torque speed characteristics, power stages, no load and blocked rotor test	
	2.3	Speed control: Classify different methods, stator voltage control using Triac, V/f control using converter inverter scheme (only block diagram)	
	2.4	Starting methods: Classification and working of different methods, high torque motors	
3.0		Single phase Induction Motor	04
	3.1	Working Principle: Double field revolving theory	
	3.2	Staring methods: Split phase, capacitor start, capacitor start and run, shaded pole,	
	3.3	Equivalent circuit: Determination of equivalent circuit parameters by no load and block rotor test.	
4.0		Permanent Magnet Synchronous Motors	04
	4.1	Working principle, EMF and torque equations	
5.0		Brushless DC Motors	04
	5.1	Unipolar brushless DC motor, Bipolar brushless DC motor, speed control, important features and applications	
6.0		Stepper Motors:	06
	6.1	Constructional features, working principle	
	6.2	Variable reluctance motor: Single and multi-stack configurations, characteristics, drive circuits	
7.0		Switched Reluctance Motors:	04
	7.1	Constructional features, working principle, operation and control requirements	
		Total	38

Recommended Books:

- 1. Bimbhra P.S., Electric Machinery, Khanna Publisher,
- 2. G.K. Dubey, Fundamentals of electrical drives, Narosa Publications
- 3. Nagrath I.J., Kothari D.P., *Electric Machines*, TMH Publishcations
- 4. A.E. Fitzgerald, Kingsly, Stephen., *Electric Machinery*, McGraw Hill
- 5. M.G. Say and E. O. Taylor, *Direct current machines*, Pitman publication
- 6. Ashfaq Husain, *Electric Machines*, Dhanpat Rai and co. publications

- 7. M.V. Deshpande, *Electric Machines*, PHI
- 8. Smarajit Ghosh, Electric Machines, PEARSON

Internal Assessment (IA):

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

End Semester Examination:

- 1. Question paper will comprise of 6 questions, each carrying 20 marks.
- 2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

SE Electronics Engineering Semester IV Syllabus of Laboratory

Subject Code	Subject Name	Te	aching Sch	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total	
EXL 401	Discrete		02			01		01	
	Electronics								
	Laboratory								

Subject	Subject Name		Examination Scheme									
Code			,	Theory Marks		Term	Practical	Oral	Total			
		Int	ernal a	ssessment	End Sem.	Work	and					
		Test	Test	Ave. Of Test	Exam		Oral					
		1	2	1 and Test 2								
EXL 401	Discrete					25	50	-	75			
	Electronics											
	Laboratory											

Syllabus: Same as **EXC402** (Discrete Electronics)

Term Work:

At least 10 experiments based on the entire syllabus of Subject **EXC402** (**Discrete Electronics**) should be set to have well predefined inference and conclusion. Computation/simulation based experiments are encouraged. Therefore, minimum of 05 simulation experiments be carried out (out of total 10 Expts.) The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every experiment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Suggested Experiments on Simulation:

- 1. One SPICE simulations and implementation for BJT and FET DC biasing (Design and Testing)
- 2. One SPICE simulation and implementation for an Amplifier Design and Testing with measurement of input and output impedance.
- 3. One SPICE simulation and implementation for Frequency response of cascaded and single stage amplifiers.
- 4. One SPICE simulation and implementation for Oscillators.
- 5. One SPICE simulation and implementation for Negative feedback amplifiers.
- 6. One SPICE simulation for Differential amplifier with active load.
- 7. One SPICE simulation for power amplifier.
- 8. One SPICE simulation for Darlington/cascode amplifier.

Subject Code	Subject Name	Te	aching Sch	eme	Credits Assigned					
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total		
EXL 402	Microprocessor and Peripherals Laboratory		02			01		01		

Subject	Subject Name		Examination Scheme									
Code			T	heory Marks		Term	Practical	Oral	Total			
		Int	ternal a	ssessment	End	Work	and					
		Test	Test	Ave. Of Test	Sem.		Oral					
		1	2	1 and Test 2	Exam							
EXL 402	Microprocessor and					25		25	50			
	Peripherals											
	Laboratory											

Syllabus: Same as EXC 403 (Microprocessor and Peripherals)

Term Work:

At least 10 experiments based on the entire syllabus of EXC 403 (Microprocessor and

Peripherals) should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the **overall performance** of the student with **every experiment graded from time to time.** The grades should be converted into marks as per the **Credit and Grading System** manual and should be **added and averaged**. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Suggested Experiments

- 1. Write a program to arrange block of data in i) Ascending and (ii) Descending order.
- 2. Write a program to find out any power of a number
- 3. Write a programmable delay
- 4. Write a program to find out largest number in an array.
- 5. Experiment on String instructions (e.g Reversing of string & palindrome)
- 6. Write a programme to multiply 32 bit numbers
- 7. Menu driven programming
- 8. Write a program for code conversion
- 9. Programming the 8255 to read or write to port (any one application)
- 10. Programming the 8259 to demonstrate rotating priority, Specific priority ,etc

Subject Code	Subject Name	Te	aching Sch	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total	
EXL 403	Control Systems and Electrical Machines Laboratory		02			01		01	

Subject	Subject Name	Examination Scheme								
Code			T	heory Marks	Term	Practical	Oral	Total		
		Internal assessment Er				Work	and			
		Test Test Ave. Of Test		Sem.		Oral				
		1	2	1 and Test 2	Exam					
EXL 403	Control Systems					25		25	50	
	and Electrical									
	Machines									
	Laboratory									

Syllabus: EXC 404 (Principles of Control Systems) 07 Experiments and
EXC 406 (Electrical Machines) 03 Experiments

Term Work:

At least 03 experiments on EXC 406 (Electrical Machines) and 07 experiments on EXC 404 (Principles of Control Systems) based on the entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades should be converted into marks as per the Credit and Grading System manual and should be added and averaged. The grading and term work assessment should be done based on this scheme. The final certification and acceptance of term work ensures satisfactory performance of laboratory work and

minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.

Subject Code	Subject Name	Те	aching Sch	eme	Credits Assigned				
		Theory	Practical	Tutorial	Theory	TW	Tutorial	Total	
EXL 404	Communication		02			01		01	
	Engineering								
	Laboratory								

Subject	Subject Name	Examination Scheme								
Code		Theory Marks					Practical	Oral	Total	
		Int	ernal a	ssessment	End Sem.	Work	and			
		Test Test Ave. Of Test		Exam		Oral				
		1	2	1 and Test 2						
EXL 404	Communication					25	50		75	
	Engineering									
	Laboratory									

Syllabus: Same as EXC 405 (Fundamentals of Communication Engineering)

Term Work:

At least 10 experiments based on entire syllabus of EXC 405 (Fundamentals of Communication Engineering) should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative. Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades should be converted into marks as per the Credit and Grading System manual and should be added and averaged. The grading and term work assessment should be done based on this scheme.

The final certification and acceptance of term work ensures satisfactory performance of laboratory work and minimum passing marks in term work. Practical and Oral exam will be based on the entire syllabus.